2023년 2월 15일(수), 16:00-17:45
Room K (다이아몬드 I, 6층)

F. Silicon and Group-IV Devices and Integration Technology 분과
[WK3-F] Neuromorphic Devices and Reliability

좌장: 구민석 교수(인천대학교), 권지민 교수(UNIST)

WK3-F-1 **16:00-16:15**	**Ultra-Low-Power Neuromorphic Computing based on Fully Si-Compatible Chip Technology and Application for Convolutional Neural Network** Kannan Udaya Mohanan[1], Min-Kyu Park[2], Jong-Ho Lee[2], and Seongjae Cho[1] *[1]Department of Electronic Engineering, Gachon University, [2]Department of Electrical and Computer Engineering, Seoul National University*
WK3-F-2 **16:15-16:30**	**Analysis of the Current Mirroring Method for Accurate AND-Type Hardware-Based Neural Network Systems** Yeonwoo Kim[1,2], Donghyun Ryu[1,2], and Woo Young Choi[1,2] *[1]Department of Electrical and Computer Engineering, Seoul National University, [2]Inter-university Semiconductor Research Center, Seoul National University*
WK3-F-3 **16:30-16:45**	**Compensation-Circuit-Added Current Mirrors for SNN Accuracy Improvement** Jonghyuk Park[1,2], Kyungchul Park[1,2], and Woo Young Choi[1,2] *[1]Department of Electrical and Computer Engineering, Seoul National University, [2]Inter-university Semiconductor Research Center, Seoul National University*
WK3-F-4 **16:45-17:00**	**Influence of Weight Transfer Error on Vector-Matrix Multiplication Operation** Junsu Yu[1,2], Sungmin Hwang[1,2], Taejin Jang[1,2], and Woo Young Choi[1,2] *[1]Department of Electrical and Computer Engineering, Seoul National University, [2]Inter-university Semiconductor Research Center, Seoul National University*
WK3-F-5 **17:00-17:15**	**The Effect of Fluorine Implantation on NBTI and Off Current in PMOS** Chang-Hun Han, Jong-Min Kim, Hyeon-Jeong Kang, Tae-Wook Kang, and Man-Lyun Ha *DB HiTek*
WK3-F-6 **17:15-17:30**	**Performance Enhancement Method of Line Tunnel Field-Effect (TFET) Using Hot Carrier Degradation** Jae Seung Woo[1,2] and Woo Young Choi[1,2] *[1]Department of Electrical and Computer Engineering, Seoul National University, [2]Inter-university Semiconductor Research Center, Seoul National University*
WK3-F-7 **17:30-17:45**	**Low-Temperature Deuterium Annealing to Recover Total Ionizing Dose-Induced Gate Dielectric Damage in MOSFETs** Dong-Hyun Wang, Sung-Su Yoon, Dae-Han Jung, Ja-Yun Ku, Khwang-Sun Lee, Jae-Hun Kim, Tae-Hyun Kil, and Jun-Young Park *Chungbuk National University*